

## CLAIMS

What is claimed is:

- 1           1.     A method for calibrating a device, the device comprising a plurality of  
2 transconductor cells, the method comprising the steps of:  
3               (a)     generating a test signal to the device; and  
4               (b)     suppressing even-order harmonics due to transistor mismatches within  
5 the plurality of transconductor cells.
  
- 1           2.     The method according to claim 1 wherein the suppressing step (b) comprises  
2 the step of (b1) introducing an offset voltage on an amplifier in the plurality of transconductor  
3 cells that controls the drain to source voltage of the input transistors.
  
- 1           3.     The method of claim 2, wherein the offset voltage is controlled by a DSP in  
2 order to minimize the even order harmonics upon the application of the test signal on the  
3 device.
  
- 1           4.     The method of claim 1 wherein the device comprises a second order low pass  
2 filter.
  
- 1           5.     The method of claim 1 wherein the test signal comprises a sinusoidal test  
2 signal.

1           6.     A calibration system comprising a device, the device including a plurality of  
2 transconductor cells; and

3                 a digital signal processor (DSP), the DSP for generating a test signal to the  
4 device and for suppressing even order harmonics due to transistor mismatches within the  
5 plurality of transconductor cells.

1           7.     The system of claim 6 wherein the DSP introduces an offset voltage to each  
2 amplifier in a plurality of transconductor cells that control the drain to source voltage of the  
3 input transistors of the cells.

1           8.     The system of claim 6 wherein the device comprises a second order low pass  
2 filter.

1           9.     The system of claim 7 wherein the DSP controls the offset voltage in order to  
2 minimize the even order harmonics upon the application of the test signal on the device.

1           10.    The system of claim 6 wherein the test signal comprises a sinusoidal test signal.